

Evaluating the Durability of Balance of Systems Components Using C-AST

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The Motivation for the BoS Study

- BoS components include: connectors, cables,
 branch connectors, fuses (discrete), fuse blocks.
- Durability of BoS components has very limited research examination.





- Consequences of degradation and failure: module offline, string offline, tripped inverter, system shutdown, arc fault, fire!!!
- With limited publicity, latter consequences are BoS-centric.



Example of PV fires in Italy. Fiorentini et. al., PVRW 2020.



Goals of the C-AST Project

General:

C-AST typically used with MiMos, so:

- -Develop characterization methods.
- -Identify degradation modes.
- -Demonstrate ability to distinguish known bad components using C-AST.

Specific:

- -Identify most damaging stressors (environments, from C-AST sequences).
- -Can static load or mechanical vibration contribute to failure?



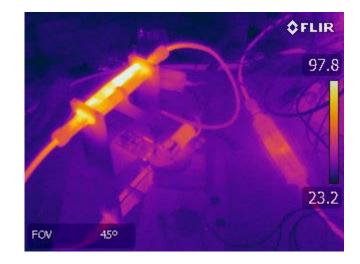
C-AST chamber during operation (MiMo test sites).

Look For in This Presentation

-External mechanical actuation greatly affected the result.-

• How is examination implemented?

What component(s) are affected?



How to further validate the result?

Optional encore slides on j-box adhesives & pottants.

Branch Connectors: The Scenario







- Utility provider experiencing ~30% failure rate in their power transfer chain, attributed to branch connectors.
 - -"Failure" means overheating, softening, physical distortion.
 - -Observable ΔT in thermographic imaging.
 - -Worst consequence: broken circuit, arc, fire.
- Component makes & models kept confidential in this presentation.







Branch Connectors: The Approach







- Compare C-AST to UL standard tests.
- # and contribution of bad components unknown. Evaluate proximate system components: cable connectors, fuse, branch connectors.
- Develop fixture and software using benchtop experiments (1 replicate).
- Use custom C-AST fixture for mechanical actuation (6 replicates).

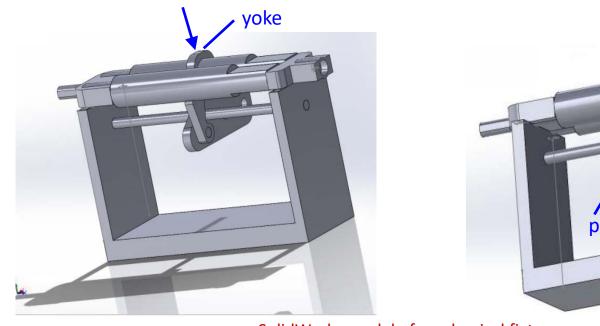


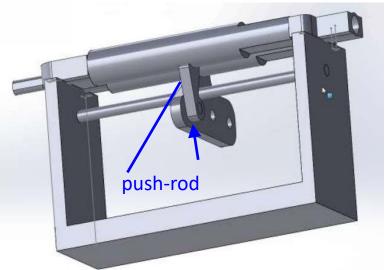




A Benchtop, Sample Integrated Push/Pull Mechanical Fixture Was Used

- "Yoke and push-rod" concept design concept was selected. (vs. "wedge").
- Specimen assembly is part of the actuation mechanism.
- Deflection used: 3 mm (initial) \rightarrow 1 mm \rightarrow 0.5 mm (C-AST).
- Benchtop version run with 16 rpm DC motor.
- C-AST version uses hydraulic actuators, 1/8 10 Hz.

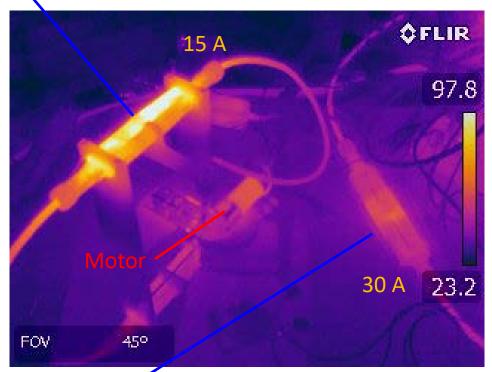




SolidWorks model of mechanical fixture

Mechanical Actuation Readily Affected Test Results

Dynamic (actuated) sample assembly



Static (unactuated) assembly

Operation:

- Start at 10 A / 20 A applied DC current.
- Current incremented 1 A each day to failure.

Observed limits:

- Static assembly: fails at 35 A (equiv. labels for 30 A).
- Dynamic assembly: fails at 15 A. T_{external} > 130°C.
- UL connector test: no failure BC @ 37.5 A. T_{external} 44°C.

Failure modes:

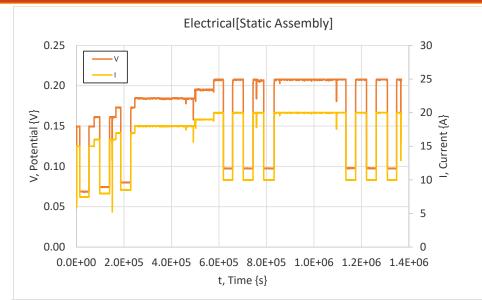
- Static assembly: fails at fuse (open circuit).
- Dynamic assembly: fails at fuse/branch.
- -Local arcing suspected from: smoke, local melting of plastic, discolored metal pins, increased fuse resistance.

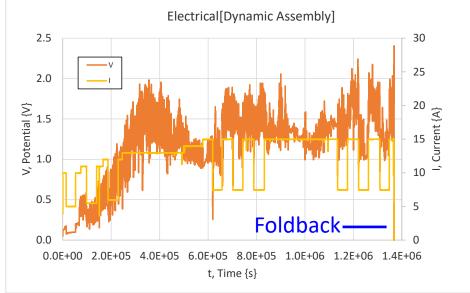
I-V: Mechanical Actuation Gave an Immediate, On-going Affect

- LabView software for C-AST developed in benchtop experiments.
- I, V are logged per sample assembly.
- Data binned & analyzed in 1 minute intervals.
- Optional "burst" mode to log @ 100 kHz.

- Example (δ =1 mm) compares I, V for static & dynamic assemblies.
 - -I, V scales (y-axis) are different, static vs. dynamic.
 - -V quickly becomes more variable for dynamic.

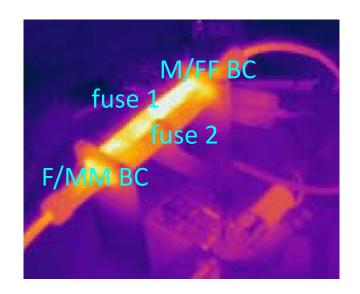
- Foldback protection (> V_{fb}) was extended from 1 to 5 to 25 s.
- Q: what would you use to simulate an inverter?



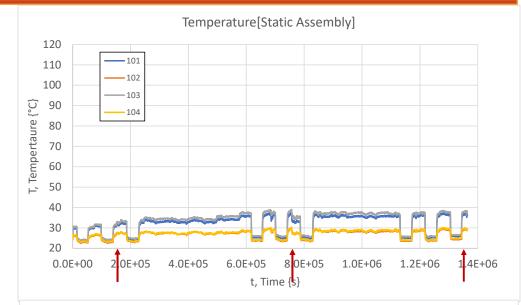


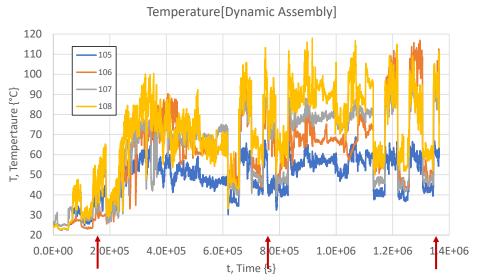
T: Mechanical Actuation Gave an Immediate, On-going Affect

- T is logged per site (F/MM BC, fuse 1, fuse 2, M/FF BC).
 - -Discrete T-type thermocouples in sheet package.



- Example (δ =1 mm) compares T for static & dynamic assemblies.
 - -Scale (y-axis) same for static & dynamic.
 - -FLIR vs. TC: exact hottest spot difficult to predict.
 - -Helpful to know: t_{onset}, what components affected.





Data from experiment 4. Red arrows indicate approximate read point for FLIR imaging.

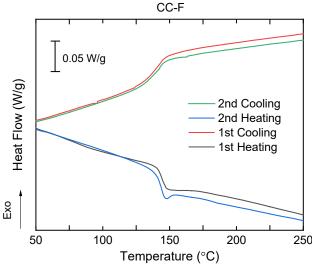


DSC & FTIR Identify Connector Ends Are Polycarbonate

Q: What is the phase transition temperature, what material is implied for black deformed plastic?

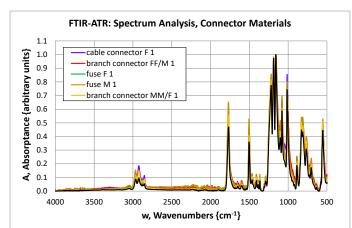
→DSC and FTIR examination of unaged samples.

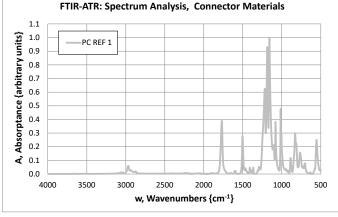
- •Suspect hard structural polymer (PC, ABS, etc) from handling samples.
- $\bullet T_{glass}$ of 142±5°C (AVG ± 2 S.D.) suggests material is amorphous PC.
- •All samples gave similar response (scans from -90 200 °C), including: cable connector, branch connector, fuse connector ends.



DSC for cable connector, female end (plastic).

- •Cable-, branch-, fuse- connectors have same FTIR spectra.
 - -Similar to polycarbonate reference sample.
 - -2 measurements from separate pieces each component.
 - -FTIR spectra verified on both F and M connector ends.
- ⇒Suspect PC containing carbon black.



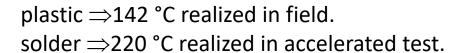


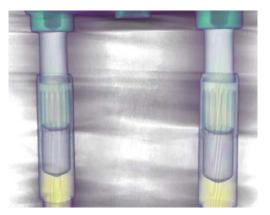
FTIR (left) for all component ends and (right) PC reference.

XCT: Different Sample Locations, Temperatures May Dominate Between Field & "C-AST"

- Figures: X-ray Computed Tomography imaging of field- and accelerated tested-samples.
- •Field samples show asymmetry not present on unaged samples.
- Accelerated samples: bulge + contrast proximate to solder.

- •Convolute spring component shape unchanged.
 - T_{forge} Cu ~900°C. T_{melt} Cu 1085°C.
- Aluminum bronze fuse holder shape unchanged.
 - $T_{softening}$ Al/Cu ~315°C. T_{melt} Al/Cu >550°C.
- •Solder may contribute to failure.
 - T_{melt} Sn/Ag/?Cu? ~220°C.

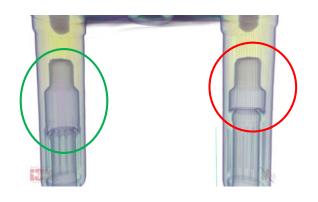




Unaged metal pins, utility provider (opposite end)



Unaged metal pins, utility provider.



Metal pins, utility provider.



Metal pins, benchtop δ = 3 mm.

The Destructive Failure Analysis Procedure Following XCT

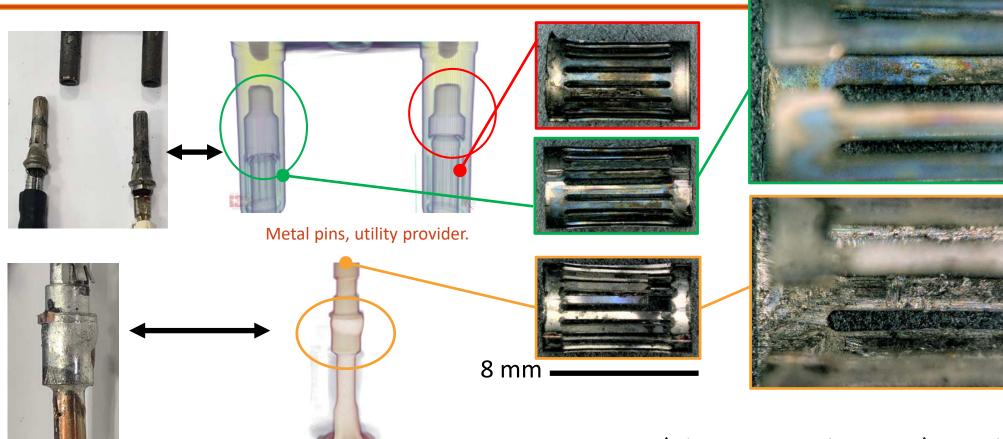
- 1. Remove (mill) external plastic.
 - -Retain plastic for F/A (FTIR, DSC).
 - -Inspect internal metal components relative to XCT.
 - -Methods: camera, optical microscopy, SEM/EDX.
- 2. Extract (cut, unfold) convolute spring from F metal pins.
 - -Inspection, methods as above.

convolute spring, extracted from unaged metal pin



~8 mm

Optical Micrscopy: Oxidation of Spring, with Mechanical Wear for δ = 3 mm



Metal pins, benchtop δ = 3 mm.

- Both: appearance (discolored, distorted) consistent with XCT.
- Discoloration suggests oxidation of convolute springs. (ΔT).
 - -More localized discoloration in benchtop specimen.
- Scuff marks (ends, interior) suggest wear during accelerated test.

Present Status

Branch Connectors:

- On-going failure analysis: solder vs. spring, δ = 1 mm.
 - -Do we still see wear?
- Static assembly branch connectors through round 1 of C-AST (10 A).
- Dynamic C-AST branch connector assembly pending.
 - -Will effect of mechanical actuation be observed as in benchtop experiments?
 - -Will effect of weathering be observed?
- May apply second round of C-AST (increased current).
- Final comparison at IEEE PVSC 2022.

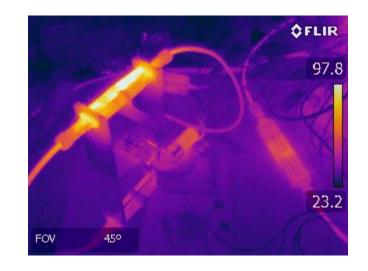
Remember From This Presentation

-External mechanical actuation greatly affected the result.-

- How is examination implemented?
 - -sample integrated push/pull mechanical fixture
- What component(s) are affected?
 - -static: fuse (internal).
 - -with actuation: BC/fuse (observed for field).



- -mechanical wear observed for δ = 3mm.
- -pending C-AST @ δ = 0.5mm.



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